

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

**APPLICANTS** : Jong-Cheol Lee, et al.    **ATTY DOCKET NO.** : 8836-223JHM/ID12244US  
**SERIAL NO.** : 10/748,906    **EXAMINER** : Saqib Javaid Siddiqui  
**FILED** : December 30, 2003    **ART UNIT** : 2138  
**TITLE** : *SEMICONDUCTOR MEMORY DEVICE TESTABLE WITH A SINGLE DATA RATE AND/OR  
DUAL DATA RATE PATTERN IN A MERGED DATA INPUT/OUTPUT PIN TEST MODE*

MAIL STOP: AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT AFTER FINAL ACTION UNDER 37 CFR 1.116**

**S I R :**

In response to the Official Action of July 10, 2007, applicants respectfully request that the above-identified application be amended as follows.

Amendments to the claims are reflected in the Listing of Claims that begins on page 2 of this Amendment.

The Remarks portion begins on page 6 of this Amendment.